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Application Number	10/538,739			
Filing Date	12/15/2003			
First Named Inventor	Yasuhiro OKAMOTO			
Art Unit	2814			
Examiner Name	Sarah Kate Salerno			
Attorney Docket Number	029437-0108			

U.S. PATENT DOCUMENTS					
Examiner Cite Document Numbe		Document Number	Publication Date	Name of Patentee or Applicant of	Pages, Columns, Lines, Where Relevant
	No.1	Number-Kind Code <sup>2</sup> (if known)	MM-DD-YYYY	Cited Document	Passages or Relevant Figures Appear

UNPUBLISHED U.S. PATENT APPLICATION DOCUMENTS					
Examiner Initials*	Cite No.1	U.S. Patent Application Document Serial Number-Kind Code <sup>2</sup> (if known)	Filing Date of Cited Document MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document Country Code <sup>3</sup> Number <sup>4</sup> Kind Code <sup>5</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Documents	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sub>6</sub>
	B1	JP 2002-359256A	12-13-2002	FUJITSU LTD.		
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	NON PATENT LITERATURE DOCUMENTS				
Examiner Initials*	tem (book magazine journal serial symnosium catalog etc.) date nage(s) volume-issue numbi				
	B2	LI et al., "High breakdown voltage GaN HFET with field plate," Electronics Letters, February 1, 2001, Vol. 37, No. 3, pp. 196-197.			
	В3	TAN et al., "The Effect of Dielectric Stress on the Electrical Characteristics of AlGaN/GaN Heterostructure Field-Effect Transistors (HFETs)," The 10 <sup>th</sup> IEEE International Symposium on Electron Devices for Microwave and Optelectronic Applications, November 2002, pp. 130-135.			
	B4	ZHANG,N.Q. et al., "Effects of surface traps on breakdown voltage and switching speed of GaN power switching HEMTs," 2001 IEEE, pp. 25.5.1-25.5.4.			

		Data	07/00/0000
Examiner Signature	/Sarah Salerno/	Date Considered	07/08/2008

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